

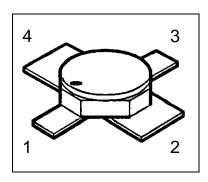
BFY740B-02(ES)

Features

- High gain ultra low noise RF transistor
- Outstanding noise figure F = 0.65 dB at 1.8 GHz

F = 1.05 dB at 6 GHz F = 1.50 dB at 10 GHz F = 1.60 dB at 12 GHz

Hermetically sealed microwave package



Product validation

• **@esa** Space Qualified

ESCC Detail Spec. No.: 5611/011 Type Variant No. 02

Description

ESD: Electrostatic discharge sensitive device, observe handling precautions!

Table 1 Product information

Туре	Comment	Pin Config	Package			
		1	2	3	4	
BFY740B-02(ES)	For flight use	6	E	Б	E	Micro-X
BFY740B-02(P) ¹	Not for flight use ¹			В		

¹ (P) parts have the same fit, form and function as (ES) parts, no screening acc. to Chart F3 in ESCC Generic Specification No. 5010

BFY740B-02(ES)

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Maximum ratings



1 Maximum ratings

Table 2 Maximum ratings

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Тур.	Max.		
Collector-emitter voltage	V_{CEO}	-	-	4	V	<i>T</i> _A > 0 °C
		-	-	3.5		T _A ≤ 0 °C
Collector-base voltage	V_{CBO}	-	-	13	V	
Emitter-base voltage	V_{EBO}	-	-	1.2	V	
Collector current	Ic	-	-	30	mA	
Base current ¹	I _B	-	-	3	mA	
Total power dissipation ²	P _{tot}	-	-	120	mW	<i>T</i> _S ≤ 125 °C
Junction temperature	T _j	-	-	175	°C	
Operating temperature	T_{op}	-65	-	175	°C	
Storage temperature	$T_{ m stg}$	-65	-	175	°C	

¹ Maximum ratings must not be exceeded under any combination of DC ratings and RF voltage/current swings except as specified in §3

 $^{^2}$ For T_S > 125 °C derating is required. T_S is measured on the collector lead at the soldering point to the PCB

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Thermal characteristics



2 Thermal characteristics

Table 3 Thermal characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition	
		Min.	Тур.	Max.			
Thermal resistance, junction –soldering point	$R_{th,JS}$	-	-	400	K/W	T _S is measured on the collector lead at the soldering point to the PCB	
Soldering Temperature	T_{sol}	-	-	250	°C	Duration 5 seconds maximum at a distance of not less than 0.5mm from the device body and the same lead shall not be resoldered until 3 minutes have elapsed.	

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Electrical characteristics



3 Electrical characteristics

at T_A=25°C, unless otherwise specified

Table 4 Static characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Тур.	Max.		
Collector-base cutoff current	I _{CBO}	-	-	10	μΑ	$V_{\rm CB} = 5V, I_{\rm E} = 0A$
Collector-emitter cutoff current ¹	I _{CEX}	-	-	200	μΑ	$V_{CE} = 4V, I_{B} = 0.1 \mu A$
Emitter base cuttoff current	I _{EBO}	-	-	5	μΑ	$V_{\rm EB} = 1.2 \text{V}, I_{\rm C} = 0 \text{A}$
DC current gain	h _{FE}	170	280	400	-	$I_{\rm C} = 20 {\rm mA}, V_{\rm CE} = 3 {\rm V}$

Table 5 Dynamic characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition	
		Min. Typ.		Max.			
Collector-base capacitance	ССВ	-	0.07	-	pF	V_{CB} = 2V, V_{BE} = vbe= 0, f= 1MHz	
Collector-emitter capacitance	C _{CE}	-	0.45	-	pF	V _{CE} = 2V, V _{BE} = vbe= 0, f= 1MHz	
Emitter-base capacitance	C _{EB}	-	0.6	-	pF	V_{EB} =0.5V, V_{CB} = vcb= 0, f= 1MHz	
Noise Figure $(Z_S = Z_{Sopt})$	F	- - - -	0.65 1.05 1.5 1.6	- - -	dB	I_{C} = 8mA, V_{CE} = 3V, f = 1.8GHz I_{C} = 8mA, V_{CE} = 3V, f = 6.0GHz I_{C} = 8mA, V_{CE} = 3V, f = 10GHz I_{C} = 8mA, V_{CE} = 3V, f = 12GHz	
Insertion power gain $(Z_S = Z_L = 50\Omega)$	S _{21e} ²		24 14 9 7	- - -	dB	I_{C} = 20mA, V_{CE} = 3V, f = 1.8GHz I_{C} = 20mA, V_{CE} = 3V, f = 6.0GHz I_{C} = 20mA, V_{CE} = 3V, f = 10GHz I_{C} = 20mA, V_{CE} = 3V, f = 14GHz	
Power Gain ²	G_{ms}	-	26.5	-	dB	I_{C} = 20mA, V_{CE} = 3V, f = 1.8GHz, Z_{S} = Z_{Sopt} , Z_{L} = Z_{Lopt}	
Power Gain ²	G_{ma}	-	19 15	-	dB	I_{C} = 20mA, V_{CE} = 3V, f = 6.0GHz, Z_{S} = Z_{Sopt} , Z_{L} = Z_{Lopt} I_{C} = 20mA, V_{CE} = 3V, f = 10GHz,	
Output power	Pout	-	14.8	-	dBm	$Z_S = Z_{Sopt}, Z_L = Z_{Lopt}$ $I_C = 20$ mA, $V_{CE} = 3$ V, $f = 1.8$ GHz, $P_{in} = 0$ dBm	

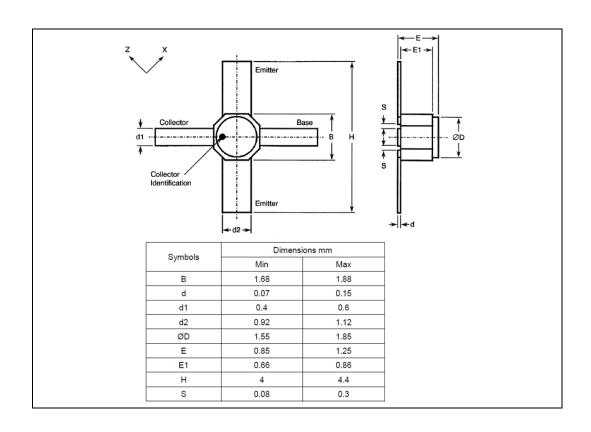
¹ This test assures $V_{(BR)CE0} > 4V$

 $^{^{2}}G_{ma} = \left| \frac{S21}{S12} \right| (k - \sqrt{k^{2} - 1}), G_{ms} = \left| \frac{S21}{S12} \right|$

Package outlines



4 Package outlines



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